

**Search Notes**

Application/Control No.

10/024,606

Examiner

Jia W. Lu

Applicant(s)/Patent under  
Reexamination

KAKU ET AL.

Art Unit

2634

**SEARCHED**

Class	Subclass	Date	Examiner
375	229	2/7/2005	JL
333	18	1/28/2005	JL
333	28	1/28/2005	JL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	229	2/7/2005	JL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	1/28/2005	JL
INVENTORSHIP	1/28/2005	JL